TOSHIBA PHOTOCOUPLER GaAlAs Ired & PHOTO-IC

TLP2116

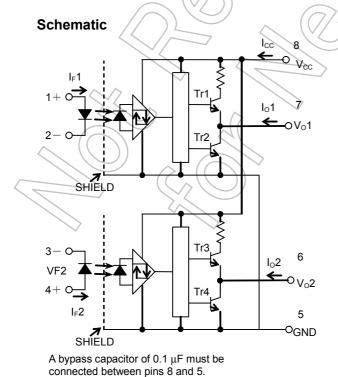
- Plasma Display Panels (PDP)
- High-Speed Interfaces
- Factory Automation (FA)

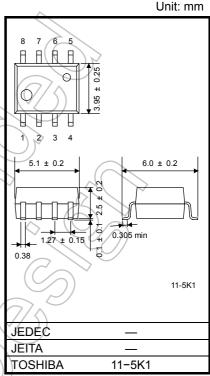
The TOSHIBA TLP2116 dual photocoupler consists of a pair of GaAlAs light-emitting diodes optically coupled to integrated high gain and high-speed photodetectors.

- Inverter logic (totem-pole output)
- Package: SO8
- Guaranteed performance over temperature : -40 to 100°C
- Power supply voltage: 4.5 to 5.5 V
- Input thresholds current: I_{FHI} = 5 mA (max)
- Propagation delay time (tpHL/tpLH): 75 ns (max)
- Switching speed: 15 MBd (typ.) (NRZ)
- Common mode transient immunity: ±10 kV/μs
- Isolation voltage: 2500 Vrms

Truth Table

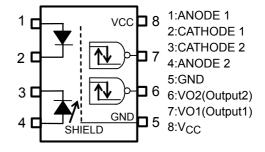
| Input | LED1(2) | Tr1(3) | Tr2(4) | Output 1(2) |
|-------|---------|--------|--------|-------------|
| Н | ON | OFF | ON |)) L |
| L | OFF | ON | OFF | H |





Weight: 0.21 g (typ.)

Pin Configuration (Top View)



Start of commercial production 2008/02

Absolute Maximum Ratings (Ta=25°C)

| | Characteristic | Symbol | Rating | Unit | |
|----------|--|---------------------|----------------------|------------|---------|
| | Forward current | (Each Channel) | lF | 20 | mA |
| ED | Forward current derating (Ta ≥ 85°C | C) (Each Channel) | ⊿l _F /⊿Ta | -0.5 | mA/°C |
| " | Peak transient forward current (Each | n Channel) (Note 1) | I _{FPT} | 1 | <u></u> |
| | Reverse voltage | (Each Channel) | V_{R} | 5 | V |
| κ | Output current | (Each Channel) | Io | 10 | (mA) |
| DETECTOR | Output voltage | (Each Channel) | Vo | 6 | V |
| | Supply voltage | | V _{CC} | 6 ((| // ŵ |
| ä | Output power dissipation | | Po | 40 | mW |
| Opera | ating temperature range | | T _{opr} | -40 to 100 | > °C |
| Stora | ge temperature range | T _{stg} | -55 to 125 |), °C | |
| Lead | solder temperature | T _{sol} | 260 | °C | |
| Isolat | ion voltage (AC,1 minute, R.H. ≤ 60%, Ta | =25°C) (Note 2) | BVS | 2500 | Vrms |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Pulse width PW \leq 1 μ s, 300pps.

Note 2: This device is regarded as a two terminal device: pins 1, 2, 3 and 4 are shorted together, as are pins 5, 6, 7 and 8.

Recommended Operating Conditions

| | | \ | | | | |
|-----------------------|----------------|----------------------|-----|------|-----|------|
| Characte | eristic | Symbol | Min | Тур. | Max | Unit |
| Input current, ON | (Each Channel) | I _{F(ON)} | 8 | 1 | 18 | mA |
| Input voltage, OFF | (Each Channel) | V _E (OFF) | 0 | 1 | 0.8 | ٧ |
| Supply voltage(*) | (Note 3) | Vcc | 4.5 | 5.0 | 5.5 | ٧ |
| Operating temperature | 7 | T _{opr} | -40 | 1 | 100 | °C |

(*) This item denotes operating ranges, not meaning of recommended operating conditions.

Note 3: The detector of this product requires power supply voltage (V_{CC}) of 4.5 V or higher for stable operation.

If the V_{CC} is lower than this value, I_{CCH} may increase, or output may be unstable.

Be sure to use the product after checking the supply current, and the operation of a power-on/-off.

Note 4: A ceramic capacitor $(0.1 \, \mu F)$ should be connected from pin 8 (V_{CC}) to pin 5 (GND) to stabilize the operation of the high gain linear amplifier. Failure to provide the bypass may impair the switching property. The total lead length between capacitor and coupler should not exceed 1 cm.

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Electrical Characteristics (Unless otherwise specified, Ta = -40 to 100° C, V_{CC} = 4.5 to 5.5V)

| Characteristic | | Symbol | Conditions | Min | Тур. | Max | Unit |
|--|----------------|----------------------|---|------|------|------|-------|
| Input forward voltage | (Each Channel) | V _F | I _F = 10 mA, Ta = 25°C | 1.3 | 1.65 | 1.75 | ٧ |
| Temperature coefficient of forward voltage | (Each Channel) | ⊿V _{F/} ⊿Ta | I _F = 10 mA | - | -2.0 | 1 | mV/°C |
| Input reverse current | (Each Channel) | I_{R} | V _R = 5 V, Ta = 25°C | | | 10 | μА |
| Input capacitance | (Each Channel) | C _T | V = 0, f = 1 MHz, Ta = 25°C | (4// | 45 | _ | pF |
| Logic low output voltage | (Each Channel) | V _{OL} | $I_{OL} = 1.6 \text{ mA}, I_F = 12 \text{ mA},$ $V_{CC} = 5 \text{ V}$ | | | 0.4 | V |
| Logic high output voltage | (Each Channel) | V _{OH} | I_{OH} = -0.02 mA, V_F = 1.05 V V_{CC} = 5 V | 4.0 | - | | V |
| Logic low supply current | | ICCL | I _F = 12 mA | _ | -8 | 10.0 | mA |
| Logic high supply current | | ICCH | V _F = 0 V (Note 3) | | (0) | 10.0 | mA |
| Input current logic low output | (Each Channel) | I _{FHL} | I_{O} =1.6 mA, V_{O} < 0.4 V | | | 5 | mA |
| Input voltage logic high output | (Each Channel) | V _{FLH} | I_{O} = -0.02 mA, V_{O} > 4.0 V | 0.8 | 2) | _ | V |

^{*}All typical values are at Ta=25°C, V_{CC} =5 V unless otherwise specified

Isolation Characteristics (Ta = 25°C)

| Characteristic | Symbol | Test Conditions | Min | Тур. | Max | Unit |
|-----------------------------|-------------------|--|--------------------|------------------|-----|--------|
| Capacitance input to output | Cs | V _S = 0, f = 1 MHz (Note 2) | _ | 8.0 | _ | pF |
| Isolation resistance | // R _S | R.H. \leq 60%, V _S = 500 V (Note 2) | 1×10 ¹² | 10 ¹⁴ | _ | Ω |
| | | AC, 1 minute | 2500 | _ | _ | Vrms |
| Isolation voltage | BVS | AC, 1 second, in oil | _ | 5000 | _ | VIIIIS |
| | | DC, 1 minute, in oil | _ | 5000 | 1 | Vdc |

Switching Characteristics (Unless otherwise specified, Ta = -40 to 100° C, V_{CC} = 4.5 to 5.5V)(Each Channel)

| Characteristic | Symbol | Test Circuit | Condi | Conditions | | Тур. | Max | Unit |
|---|-------------------------------------|-----------------|---|---|------------|------------|-----|------|
| Propagation delay time to logic low output | t _{pHL} | , | I _F = 0→12 mA | R _{IN} = 100 Ω | _ | П | 75 | ns |
| Propagation delay time to logic high output | t _{pLH} | 1 | I _F = 12→0 mA | C _L = 15 pF (Note 5) | - ((| | 75 | ns |
| Propagation delay time to logic low output | t _{pHL} | | $V_{IN} = 0 \rightarrow 5 V$ ($I_F = 0 \rightarrow 8 \text{ mA}$) | $R_{IN} = 430 \Omega$ $C_{IN} = 27 pF$ | | ((| 75 | ns |
| Propagation delay time to logic high output | t _{pLH} | 2 | $V_{IN} = 5 \rightarrow 0 \text{ V}$ (I _F = 8 \rightarrow 0 mA) | C _L = 15 pF (Note 5) | | - | 75 | ns |
| Switching time dispersion between ON and OFF | t _{рНL} - t _{рLН} | | I_F = 12 mA, R_{IN} = C_L =15 pF (Note | |) | -< | 30 | ns |
| Output fall time (90 - 10%) | t _f | 1 | I _F = 0→12 mA | R _{IN} =100 Ω | _ | 15 | 4 | ns |
| Output rise time (10 - 90%) | t _r | | I _F = 12→0 mA | C _L =15 pF (Note 5) | \Diamond | 15) | → | ns |
| Common mode transient immunity at high level output | СМН | | VC _M =1000 Vp-p V _O (min) = 4 V, | | 10000 | The second | /_ | V/μs |
| Common mode transient immunity at low level output | CML | 3 | $VC_{M} = 1000 \text{ Vp-p}$ $V_{O} \text{ (max)} = 0.4 \text{ V}$ | | -10000 |))_ | _ | V/μs |

^{*}All typical values are at Ta=25°C

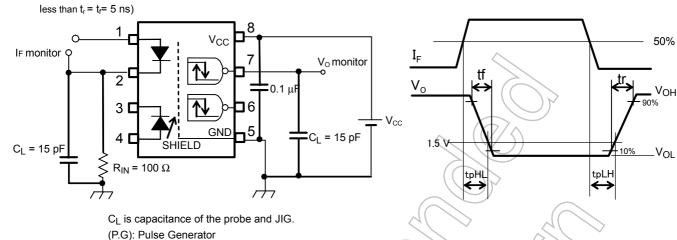
Note 5: CL is approximately 15 pF which includes probe and Jig/stray wiring capacitance.



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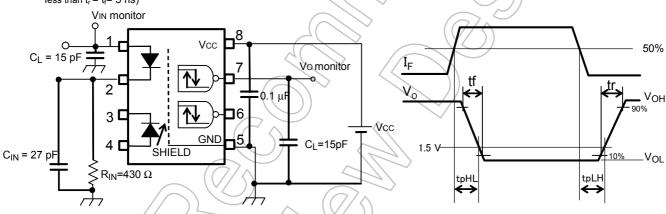
Test Circuit 1: Switching Time Test Circuit

I_F=12 mA (P.G) (f=5 MHz, duty=50%,



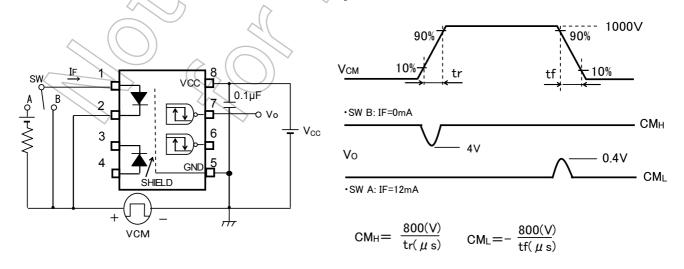
Test Circuit 2: Switching Time Test Circuit

VIN=5V (P.G) (f=5 MHz, duty=50%, less than $t_r = t_f = 5$ ns)



C_L is capacitance of the probe and JIG. (P.G): Pulse Generator

Test Circuit 3: Common-Mode Transient Immunity Test Circuit



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